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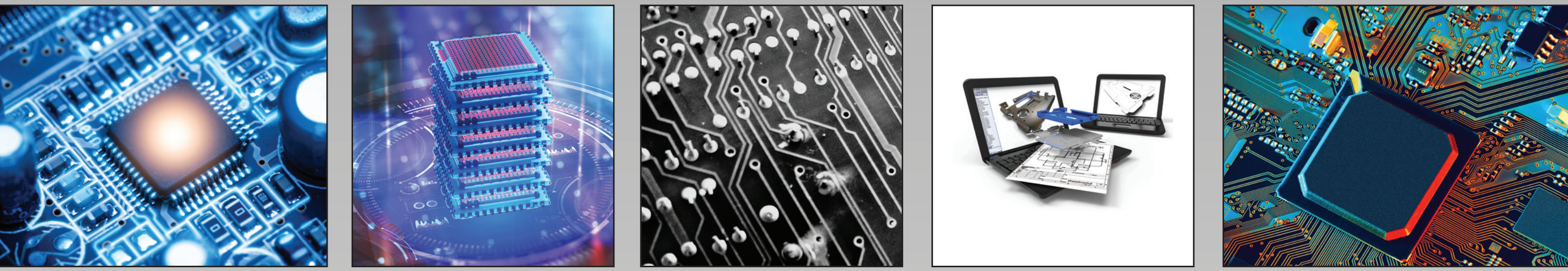
CMOS



Circuit Design, Layout, and Simulation

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